

Notic of R ferences Cited	Application/Control No. 09/995,423	Applicant(s)/Patent Under Reexamination FANG, WEN-CHI	
	Examiner Hai L. Nguyen	Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,757,212	05-1998	Sevalia, Piyush B.	327/105
X	B	US-5,095,280	03-1992	Wunner et al.	327/145
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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